

# INTERNATIONAL STANDARD

## AMENDMENT 1

**Metallic communication cable test methods –  
Part 4-3: Electromagnetic compatibility (EMC) related test method for measuring  
surface transfer impedance – Triaxial method**

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INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

ICS 33.100.10; 33.120.10

ISBN 978-2-8322-8849-8

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**METALLIC COMMUNICATION CABLE TEST METHODS –****Part 4-3: Electromagnetic compatibility (EMC) related test method  
for measuring surface transfer impedance – Triaxial method****AMENDMENT 1****FOREWORD**

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Amendment 1 to IEC 62153-4-3:2013 has been prepared by IEC Technical Committee 46: Cables, wires, waveguides, RF connectors, RF and microwave passive components and accessories.

The text of this Amendment is based on the following documents:

Draft	Report on voting
46/991/FDIS	46/1003/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Amendment is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at [www.iec.ch/members\\_experts/refdocs](http://www.iec.ch/members_experts/refdocs). The main document types developed by IEC are described in greater detail at [www.iec.ch/publications/](http://www.iec.ch/publications/).

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- reconfirmed,
- withdrawn, or
- revised.

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## 7.5 Evaluation of test results

*Add, at the end of the subclause, the following new sentence:*

In case of single pair cables where the attenuation is measured as a mixed mode scattering parameter, the conversion formula given in Annex G shall be used.

*Add, after Annex F, the following new Annex G:*

**Annex G**  
(normative)

**Single pair cables – Conversion of measured mixed mode scattering parameters to transfer impedance**

**G.1 General**

The formulae for the conversion from the measured attenuation or scattering parameter to the transfer impedance given in Clause 6 to Clause 8 are only valid for single ended measurements.

However, when measuring the transmission and mode conversion parameters of single pair cables (having a differential characteristic impedance of 100 Ω), one often measures them in a triaxial setup with a multiport network analyser with mixed mode scattering parameters. Such a test configuration is equivalent to test method B "Inner circuit with load resistor and outer circuit without damping resistor". In this case, the conversion formula has to be derived from Formula (D.2) given in Annex D.

**G.2 Conversion formula for test method B: Inner circuit with load resistor and outer circuit without damping resistor**

The conversion from measured mixed mode scattering parameter to transfer impedance of single pair cables is given by Formula ((G.1).

$$Z_T = \frac{(R_1 + Z_G)Z_R}{2\sqrt{Z_R Z_G} \times L_c} \times 10^{\frac{|S_{sc,21}|}{20}} = \frac{Z_0}{\sqrt{2} \times L_c} \times 10^{\frac{-|S_{sc,21}|}{20}} \quad (G.1)$$

where

$Z_T$  is the transfer impedance;

$R_1$  is the terminating resistor of the inner circuit (common mode),  $R_1 = Z_0/2 = 25 \Omega$ ;

$Z_G$  is the impedance of generator (common mode),  $Z_G = Z_0/2 = 25 \Omega$ ;

$Z_R$  is the impedance of the receiver (single ended),  $Z_R = Z_0 = 50 \Omega$ ;

$L_c$  is the coupling length;

$Z_0$  is the single ended system impedance,  $Z_0 = 50 \Omega$ ;

$S_{sc,21}$  is the forward transfer scattering parameter (logarithmic ratio); DUT stimulated in common mode; received power in single ended mode.

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